PCN# : P64AAAB
Issue Date : Jul. 29, 2016

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples.

Implementation of change:

Expected First Shipment Date for Changed Product :Oct. 27, 2016

Expected First Date Code of Changed Product :1644

Description of Change (From) :
Top metal composition and thickness : AlSi - 4um

Description of Change (To) :
Top metal composition and thickness : AlSiCu - 5um

Reason for Change:
- Enhance product robustness with increase of top metal composition and thickness

Affected Product(s):

FQP19N20LPWD	PCFF15H60W	PCFF15S60W
PCFF20S65W	PCFF30S65W	PCFF60UP40W
PCFF60UP60W	PCFG40N120ANW	PCFG40N65SMW
PCFQ2N60CW	PCG30N60A4W	PCR30160W
PCR8PA5W		

Qualification Plan	Device	Package	Process	No. of Lots
QP15031101	RURG8060	TO247	Diode Vehicle	3

Test Description:	Condition:	Standard :	Duration:	Results:
Pre-condition	NA	JESD22-A113	NA	NA
High Temperature Gate Bias	NA	JESD22-A108	1000 hrs	NA
High Temperature Reverse Bias	Tj=175°C, Vr = 600V	JESD22-A108	1000 hrs	0/231
High Temperature Storage Life	175°C	JESD22-A103	1000 hrs	0/231
Highly Accelerated Stress Test	130°C, 85%RH, Vr = 42V	JESD22-A110	96 hrs	0/231
Power Cycle	Delta 100CC, 2.0 Min cycle	MIL-STD-750-1036	10000 cycles	0/231
Temperature Cycle	-65°C, 150°C	JESD22-A104	500 cycles	0/231

Qualification Plan	Device	Package	Process	No. of Lots
QP15031101	FGH75T65UPD_F155	TO247	FS IGBT Vehicle	3

Test Description:	Condition:	Standard :	Duration:	Results:
Pre-condition	NA	JESD22-A113	NA	NA
High Temperature Gate Bias	Tj=175°C, Vge = 20V	JESD22-A108	1000 hrs	0/231
High Temperature Reverse Bias	Tj=175°C, Vce = 650V	JESD22-A108	1000 hrs	0/231
High Temperature Storage Life	175°C	JESD22-A103	1000 hrs	0/231
Highly Accelerated Stress Test	130°C, 85%RH, Vce = 42V	JESD22-A110	96 hrs	0/231
Power Cycle	Delta 100CC, 2.0 Min cycle	MIL-STD-750-1036	10000 cycles	0/231
Temperature Cycle	-65°C, 150°C	JESD22-A104	500 cycles	0/231

Qualification Plan	Device	Package	Process	No. of Lots
QP15031101	FCH041N60E	TO247	SuperFET2	3

Test Description:	Condition:	Standard :	Duration:	Results:
Pre-condition	NA	JESD22-A113	NA	NA
High Temperature Gate Bias	Tj=150°C, Vgs = 20V	JESD22-A108	1000 hrs	0/231
High Temperature Reverse Bias	Tj=150°C, Vds = 600V	JESD22-A108	1000 hrs	0/231
High Temperature Storage Life	150°C	JESD22-A103	1000 hrs	0/231
Highly Accelerated Stress Test	130°C, 85%RH, Vgs = 42V	JESD22-A110	96 hrs	0/231
Power Cycle	Delta 100CC, 2.0 Min cycle	MIL-STD-750-1036	10000 cycles	0/231
Temperature Cycle	-65°C, 150°C	JESD22-A104	500 cycles	0/231

Qualification Plan	Device	Package	Process	No. of Lots
QP15031101	FNA41560B4	SPM45	SPM45	3

Test Description:	Condition:	Standard :	Duration:	Results:
Pre-condition	NA	JESD22-A113	NA	NA
High Temperature Gate Bias	NA	JESD22-A108	NA	NA
High Temperature Reverse Bias	NA	JESD22-A108	NA	NA
High Temperature Storage Life	125°C	JESD22-A103	1000 hrs	0/60
Temperature Humidity Bias Test	85°C, 85%RH, Vcc 20V	JESD22-A110	1000 hrs	0/60
Power Cycle	NA	MIL-STD-750-1036	NA	NA
Temperature Cycle	-40°C, 125°C	JESD22-A104	500 cycles	0/78